



WS22P4N3P

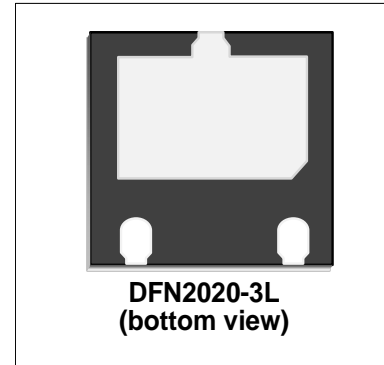
Transient Voltage Suppressor

Features

- 6600 Watts Peak Power ($t_p = 8/20\mu s$)
- Working Voltage: 22V
- Low Clamping Voltage
- Low Leakage Current

IEC COMPATIBILITY (EN61000-4)

- IEC 61000-4-2 (ESD) $\pm 30kV$ (air), $\pm 30kV$ (contact)
- IEC 61000-4-4 (EFT) 40A (5/50ns)
- IEC 61000-4-5 (Lightning) 200A (8/20 μs)



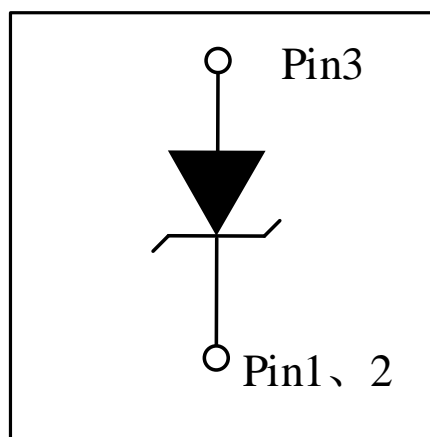
Mechanical Characteristics

- DFN2020-3L package
- Marking : Making Code
- Packaging : Tape and Reel per EIA 481
- RoHS Compliant

Applications

- I/O Interfaces
- Power lines
- Automotive and Telecommunication
- Computer & Consumer Electronics
- Industrial Electronics
- Microcontroller Input Protection

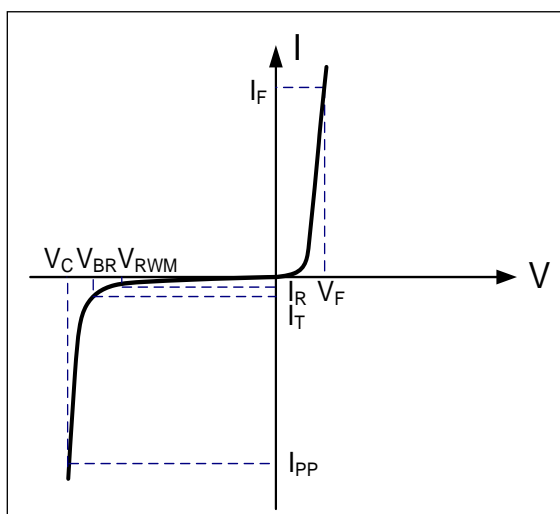
PIN Configuration



Absolute Maximum Rating			
Rating	Symbol	Value	Units
Peak Pulse Power ($t_p=8/20\mu s$)	P_{PP}	6600	Watts
Peak Pulse Current ($t_p=8/20\mu s$)	I_{PP}	200	A
Operating Temperature	T_J	-55 to +125	$^{\circ}C$
Storage Temperature	T_{STG}	-55 to +150	$^{\circ}C$

Electrical Parameters (T=25°C)

Symbol	Parameter
I_{PP}	Reverse Peak Pulse Current
V_C	Clamping Voltage @ I_{PP}
V_{RWM}	Reverse Stand-Off Voltage
I_R	Reverse Leakage Current @ V_{RWM}
V_{BR}	Breakdown Voltage @ I_T
I_T	Test Current
I_F	Forward Current
V_F	Forward Voltage @ I_F



Electrical Characteristics

WS22P4N3P						
Parameter	Symbol	Conditions	Minimum	Typical	Maximum	Units
Reverse Stand-Off Voltage	V_{RWM}				22	V
Reverse Breakdown Voltage	V_{BR}	$I_T=1mA$	23.5			V
Reverse Leakage Current	I_R	$V_{RWM}=22V, T=25^{\circ}C$			500	nA
Clamping Voltage ¹	V_C	$I_{PP}=200A, t_p=8/20\mu s$		30	33	V
Dynamic Resistance ^{2,3}	R_{DYN}	TLP=0.2/100ns		0.11		Ω
ESD Clamping Voltage ¹	V_C	$I_{PP} = 4A$ $t_p = 0.2/100ns$		26		V
ESD Clamping Voltage ¹	V_C	$I_{PP} = 16A$ $t_p = 0.2/100ns$		27.3		V
Junction Capacitance ¹	C_j	$V_R = 0V, f = 1MHz$		700	1000	pF

Notes : 1、 Measured from pin 1& pin 2 to pin 3.
 2、 TLP Setting : $t_p=100ns, t_r=0.2ns, I_{TLP}$ and V_{TLP} sample window: $t_1=70ns$ to $t_2=90ns$.
 3、 Dynamic resistance calculated from $I_{PP}=4A$ to $I_{PP}=16A$ using "Best Fit".

Typical Characteristics

Figure 1: Peak Pulse Power vs. Pulse Time

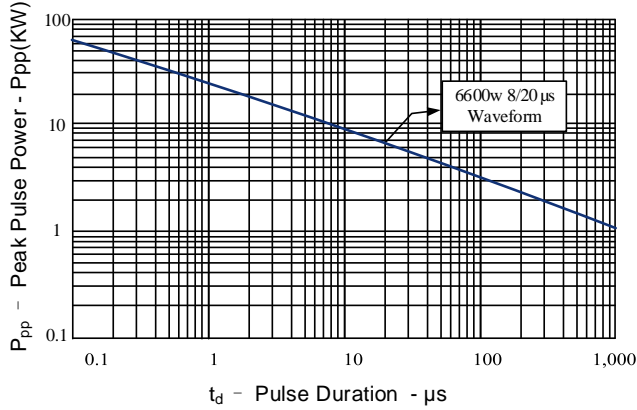


Figure 2: Power Derating Curve

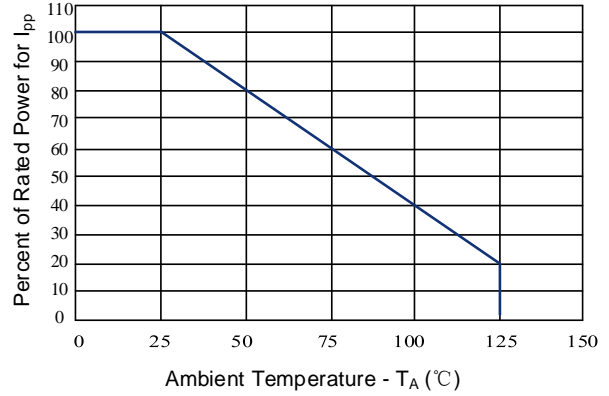


Figure 3: Clamping Voltage vs. Peak Pulse Current

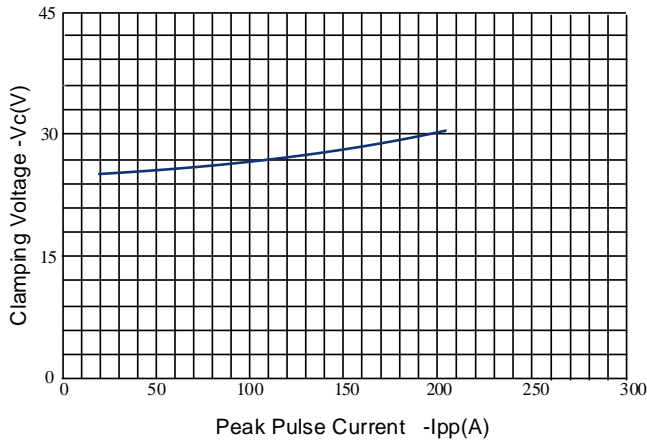


Figure 4: Normalized Junction Capacitance vs. Reverse Voltage

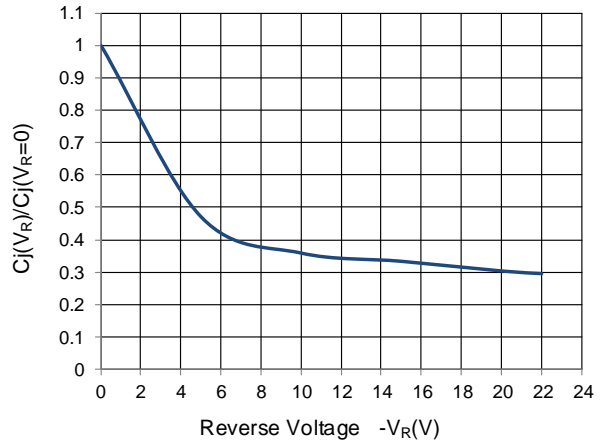


Figure 5: 8/20μs Pulse Waveform

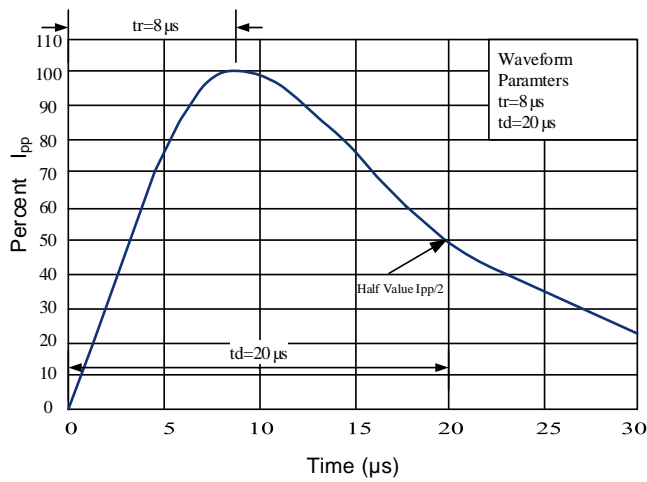
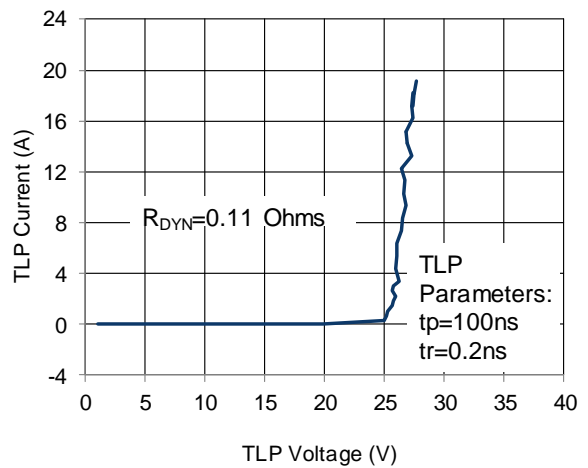
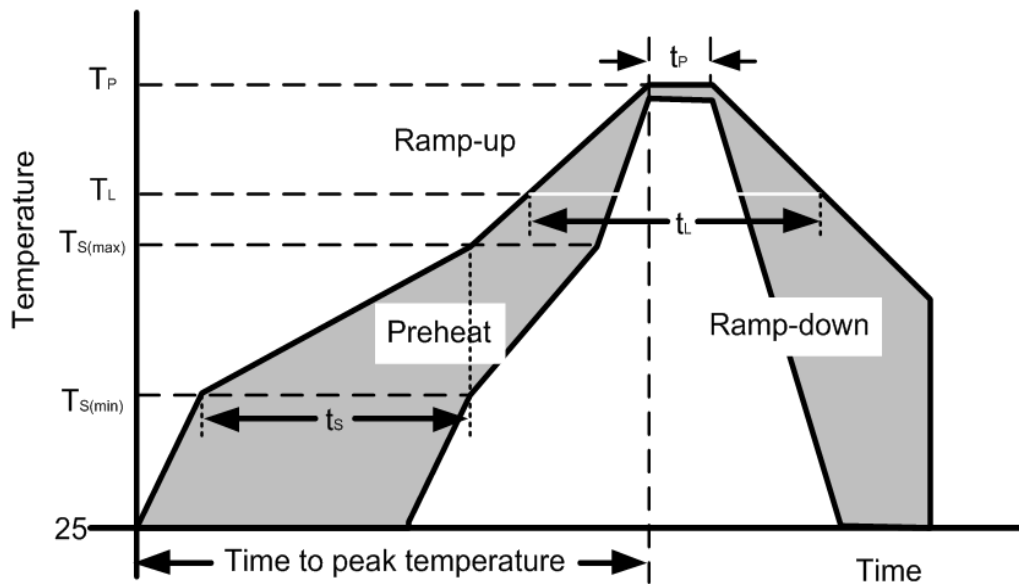


Figure 6: TLP I-V Curve



Soldering Parameters

Reflow Condition		Pb – Free assembly
Pre Heat	Temperature Min ($T_{S(min)}$)	150°C
	Temperature Max ($T_{S(max)}$)	200°C
	Time (min to max) (t_s)	60 – 190 secs
Average ramp up rate (Liquidus Temp) (T_L) to peak		5°C/second max
$T_{S(max)}$ to T_L —Ramp-up Rate		5°C/second max
Reflow	Temperature (T_L) (Liquidus)	217°C
	Temperature (t_L)	60 – 150 seconds
Peak Temperature (T_P)		260+0/-5 °C
Time within actual peak Temperature (t_p)		20 – 40 seconds
Ramp-down Rate		5°C/second max
Time 25°C to peak Temperature (T_P)		8 minutes Max.
Do not exceed		280°C



Outline Drawing –DFN2020-3L

PACKAGE OUTLINE

TOP VIEW

BOTTOM VIEW

SIDE VIEW

DFN2020-3L

SYMBOL	MILLIMETERS		
	MIN	NOM	MAX
A	0.45	0.55	0.60
A1	0.00	0.02	0.05
b	0.25	0.30	0.35
b1	0.20REF		
c	0.152REF		
D	1.90	2.00	2.10
D2	1.40	1.50	1.60
e	1.30BSC		
E	1.90	2.00	2.10
E2	0.95	1.05	1.15
E3	0.20	0.30	0.40
L	0.35	0.40	0.45
L1	0.20	0.25	0.30
h	0.20REF		
K	0.20	0.30	0.40

Land Pattern

Marking Codes

Part Number	Marking Code
WS22P4N3P	<p>M22P=Specific Device Code XXXX=Lot Code</p>

Package Information

Qty: 3k/Reel

CONTACT INFORMATION

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For additional information, please contact your local Sales Representative.

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Specifications are subject to change without notice.
The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time.
Users should verify actual device performance in their specific applications.